

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	19	statistical near analy\$4 same manufactur\$4 with wafer same quality	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 14:57
S2	2	statistical near analy\$4 same manufactur\$4 with wafer same quality and threshold	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/02/04 11:50
S3	1	average near product near quality and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 14:41
S4	39	average near quality and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 14:44
S5	597	assurance near quality and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 14:44
S6	3	assurance near quality with assess\$4 and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 14:51
S7	5	average with quality same wafer same pass\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 14:54
S8	36	average with quality same pass\$4 and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 14:55
S9	7	average with quality same (satisfy satisfied satisfactorily) and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 14:55
S10	7	average with quality same (satisfy satisfied satisfactorily satisfying) and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 14:57
S11	40	average with quality with wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 14:59
S12	3	average near quality with wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:00

S13	3	average near quality with determin\$4 same wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:00
S14	105	average near quality with determin\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:00
S15	8	average near quality with determin\$4 and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:01
S16	582	quality with determin\$4 with wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:01
S17	2	quality with determin\$4 with wafer with account	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:01
S18	2	quality with determin\$4 with wafer with affect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:01
S19	932605	fail\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:01
S20	9	quality with determin\$4 with wafer with fail\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:07
S21	18	quality with determin\$4 with wafer same fail\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:18
S22	87	average near quality and manufactur\$3 near process	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:18
S23	8	average near quality with product and manufactur\$3 near process	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:19
S24	14	average near quality with product and manufactur\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:20

S13	3	average near quality with determin\$4 same wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:00
S14	105	average near quality with determin\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:00
S15	8	average near quality with determin\$4 and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:01
S16	582	quality with determin\$4 with wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:01
S17	2	quality with determin\$4 with wafer with account	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:01
S18	2	quality with determin\$4 with wafer with affect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:01
S19	932605	fail\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:01
S20	9	quality with determin\$4 with wafer with fail\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:07
S21	18	quality with determin\$4 with wafer same fail\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:18
S22	87	average near quality and manufactur\$3 near process	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:18
S23	8	average near quality with product and manufactur\$3 near process	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:19
S24	14	average near quality with product and manufactur\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:20

S25	1	average near quality with product and manufactur\$3 and (semiconductor wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:20
S26	84	average near quality and manufactur\$3 and (semiconductor wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:20
S27	32	average near quality same (pass\$4 fail\$4 criteria criterion limit) and manufactur\$3 and (semiconductor wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:28
S28	88	average near quality same (pass\$4 fail\$4 criteria criterion limit) and manufactur\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:41
S29	5	average near quality with account and manufactur\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:42
S30	19	average near quality with account	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:44
S31	19	average near quality with account\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:44
S32	9	average near quality with affect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:46
S33	2	"6512985".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:46
S34	626	average with quality with products	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:47
S35	47	average with quality with products same (fail\$4 pass\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:48
S36	54	average with quality with product\$3 same (fail\$4 pass\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:48

S37	3	average with quality with product\$3 same (fail\$4 pass\$3) same test\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:48
S38	2	average with quality with product\$3 same (meet satisfy\$4) with (test\$4 specification criteria criterion)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:50
S39	84	average with quality same (meet satisfy\$4) with (test\$4 specification criteria criterion)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:52
S40	11	average near quality same (meet satisfy\$4) with (test\$4 specification criteria criterion)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:53
S41	172	average near quality same (((meet satisfy\$4 pass\$3 fail\$3) with (test\$4 specification criteria criterion)) bad good)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:54
S42	6	average near quality same (((meet satisfy\$4 pass\$3 fail\$3) with (test\$4 specification criteria criterion)) bad good) and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:54
S43	72	average near quality same (((meet satisfy\$4 pass\$3 fail\$3) with (test\$4 specification criteria criterion)) bad good) and (semiconductor manufactur\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 15:58
S44	8	average near quality same (((meet satisfy\$4 pass\$3 fail\$3) with (test\$4 specification criteria criterion)) bad good) and (semiconductor and manufactur\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 16:20
S45	5	average near quality with (wafer semiconductor)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 16:20
S46	266	quality with (wafer semiconductor) with lot	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 16:20
S47	4	quality with (wafer semiconductor) with lot with manufactur\$4 with average	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 16:22
S48	6	quality with (wafer semiconductor) with manufactur\$4 with average	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 16:23

S49	97	quality with (wafer semiconductor) with average	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 16:25
S50	11	average near quality same (semiconductor wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 16:26
S51	87	average near quality same device	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 16:26
S52	6	average near quality with device and manufactur\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 16:27
S53	7	average near quality with lot	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/01 16:27
S54	16	average near product near quality	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 14:58
S55	0	average near quality near wafer with produc\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 14:58
S56	2	average near quality near wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 14:59
S57	0	mean near quality near wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 14:59
S58	9	average with quality with wafer with produc\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 14:59
S59	0	average near quality with wafer with produc\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 14:59
S60	3	average near quality with wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:00

S61	1	average near quality with produc\$4 same wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:00
S62	19	average near quality with produc\$4 and (semiconductor iC wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:02
S63	4	quality near wafer with account	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:03
S64	58	quality near wafer with includ\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:03
S65	0	quality near wafer with includ\$3 with overall	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:03
S66	0	quality near wafer with includ\$3 with over near all	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:03
S67	1	quality near wafer with includ\$3 with total	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:04
S68	50	manufactur\$3 same average near quality	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:07
S69	0	manufactur\$3 same average near quality with account	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:05
S70	951	calculat\$4 with average with quality	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:07
S71	22	calculat\$4 with average near quality and manufactur\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:11
S72	6	calculat\$4 with weighted near quality and manufactur\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:19

S73	0	calculat\$4 with average near quality with wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:19
S74	0	calculat\$4 with average near quality with ic	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:19
S75	0	calculat\$4 with average near quality with semiconductor	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:20
S76	0	calculat\$4 with average near quality and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:20
S77	39	average near quality and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/04 15:20
S78	1	"6512985".pn.	US-PGPUB; USPAT	OR	OFF	2005/07/05 10:37